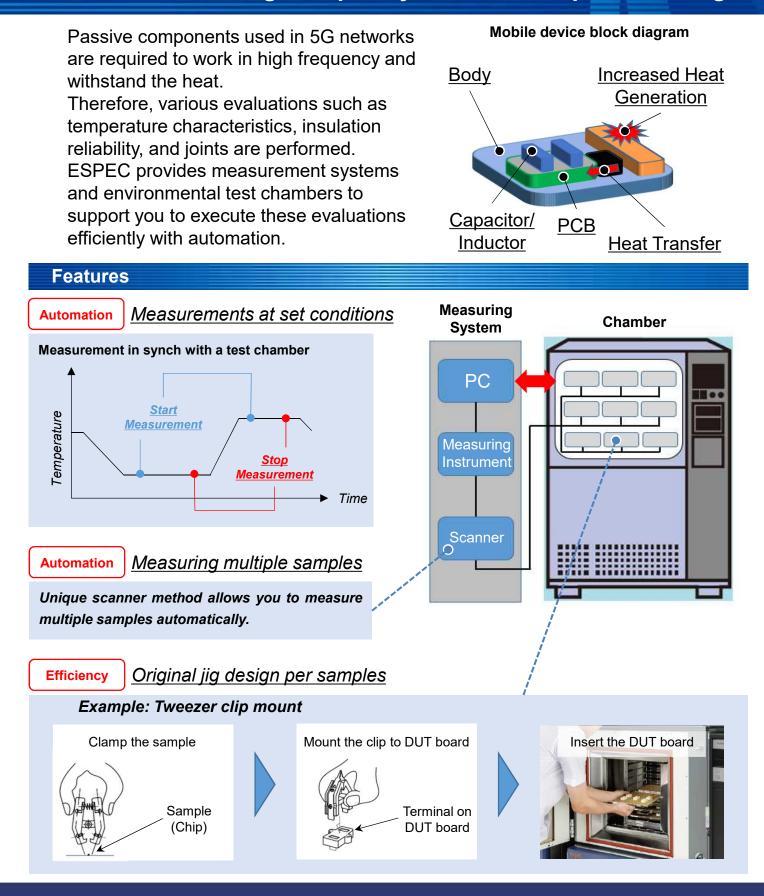
Chambers optimized for reliability assessment and temperature characteristics of capacitor and inductor with high frequency and wide temperature range

Quality is more than a word

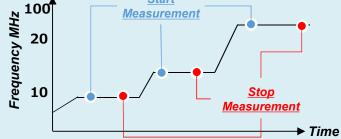


## Lineup

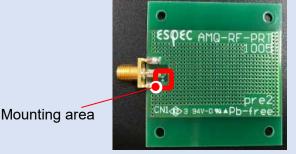
### High Frequency Inductor/Capacitor Temp. Characteristics Evaluation System Automated measuring system with 100MHz measuring frequency



Ex: Frequency characteristics Set FRQ sweep interval and take meas. Start

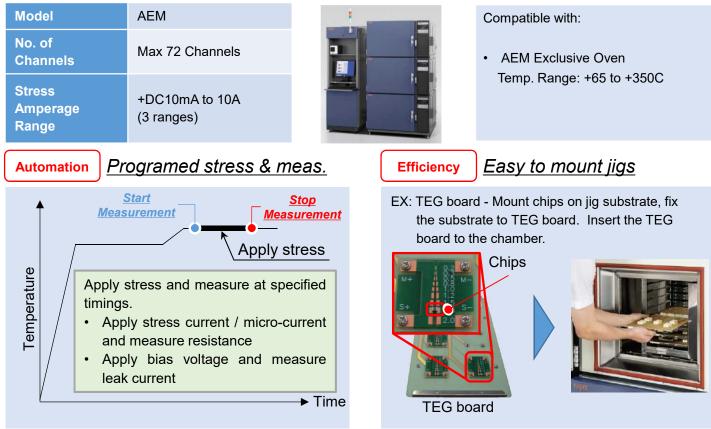


Ex: A jig for 50ohm chip impedance matching



## Multi-layer Chip Inductor Reliability Evaluation System

A constant current is applied at high temperature to accelerate the thermal distortion, and measures the change in resistance value.



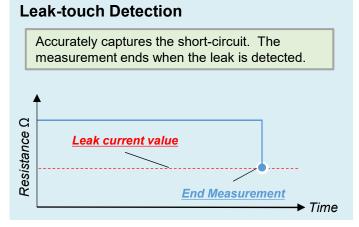
# Lineup

#### Capacitor Leakage Test System

Applies voltage under high temperature (and humidity) conditions and detects the leak current caused by insulation breakdown.

Model	AMI-U	
Number of Channels	150 channels per rack (100V / 300V / 500V / 1000V / 2500V) 300 channels per rack (100V / 300V / 500V)	
Resistance Range	$2 \ x \ 10^5$ to $1 \ x \ 10^{13} \Omega$ (with 100V stress) $2 \ x \ 10^3$ to $1 \ x \ 10^{11} \Omega$ (with 1V stress)	
Amperage Range	10pA~1mA	
Stress Voltage	100V / 300V / 500V / 1000V / 2500V	

# Automation Auto Short Circuit Detection





Compatible with:

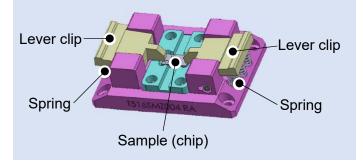
- HAST
- Bench-Top Type Temperature Chamber
- Platinous J
  - AR Series



# Jigs to minimalizing error

#### EX: Chip-probe jig

- 1. Press the lever clip and place the sample
- 2. Release the clip to secure the sample



## Conductor Resistance Evaluation System

Automatically detects cracks in the joint caused by the difference in expansion coefficient between the PCB and the component.

Model	AMR-U	
No. of Channels	Max. 280 channels per rack	
Туре	DC Current Measurement	
Resistance Range	$1\times10^{\text{-3}}{\sim}1\times10^{6}\Omega$	



Compatible with:

- Thermal Shock TSA
- Thermal Shock TSD
- TCC

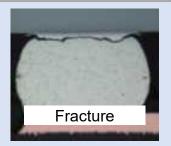
# Automation Detect disconnection by continuous monitoring of resistance

Microcracks at the joints occur at high temperatures in temperature cycle tests, but there are cases where cracks are not noticed as they reconnect at room temperature. By continuously monitoring the resistance during the test, the system can automatically judge the pass/fail of the samples by either an absolute value or change rate.









# Chamber line-up to accommodate various sample size and quantity

Product	HA	\ST	Thermal Shock TSA
Appearance			
Model	EHS-212 / 222 / 412	EHS-432 / 432L	TSA-43 / 73 / 103 / 203 / 303
Temperature Range	212 / 222: +105 to 142.9C 412: +105 to 162.2C	+105 to 162.2C	EL HOT: (ambient + 50) to 200C COLD: -65 to 0C ES / EH HOT: +60 to 200C COLD: -70 to 0C
Humidity Range	75 to 100%rh	75 to 100%rh	N/A
Internal Dimensions WHD (mm)	212/412: Φ294 x D318* (296) 222: Φ394 x D426*(404) *( )without fan-guard	<ul> <li>432: Φ548 x D560</li> <li>432-L: Φ560 x D760</li> </ul>	43:       240 x 460 x 370         73:       410 x 460 x 370         103:       650 x 460 x 370         203:       650 x 460 x 670         303:       970 x 460 x 670
Features	Efficiency         Image: Constraint of the set of th	Large Capacity Capacity: 432: 130L 432-L: 180L	<image/>

ESPEC CORP. https://www.espec.co.jp

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